

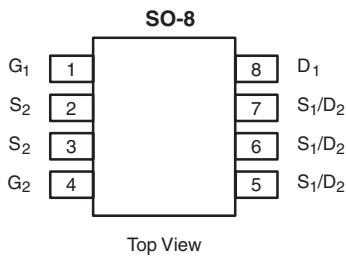
Dual N-Channel 30-V (D-S) MOSFET with Schottky Diode

PRODUCT SUMMARY

	V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A) ^a	Q_g (Typ)
Channel-1	30	0.017 at $V_{GS} = 10$ V	8.0	12.5
		0.0195 at $V_{GS} = 4.5$ V	7.5	
Channel-2	30	0.010 at $V_{GS} = 10$ V	15.2	17
		0.0115 at $V_{GS} = 4.5$ V	14.1	

SCHOTTKY PRODUCT SUMMARY

V_{DS} (V)	V_{SD} (V) Diode Forward Voltage	I_F (A) ^a
30	0.43 V at 1.0 A	3.8



Ordering Information: Si4618DY-T1-E3 (Lead (Pb)-free)

FEATURES

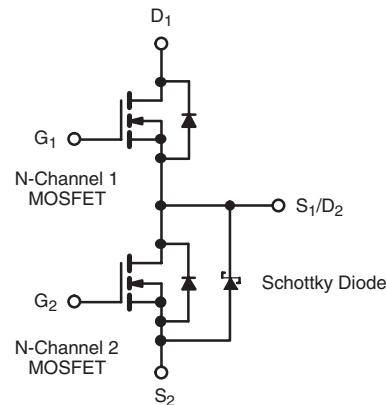
- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested



RoHS
COMPLIANT

APPLICATIONS

- Notebook Logic DC-DC
- Low Current DC-DC



ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless otherwise noted

Parameter	Symbol	Channel-1	Channel-2	Unit
Drain-Source Voltage	V_{DS}	30	30	V
Gate-Source Voltage	V_{GS}	± 16	± 16	
Continuous Drain Current ($T_J = 150$ °C)	I_D	8.0	15.2	A
		6.4	12.1	
		6.7 ^{b, c}	11.4 ^{b, c}	
		5.4 ^{b, c}	9.1 ^{b, c}	
Pulsed Drain Current (10 μ s Pulse Width)	I_{DM}	35	60	
Source-Drain Current Diode Current	I_S	1.8	3.8	
		1.25 ^{b, c}	2.4 ^{b, c}	
Pulsed Source-Drain Current	I_{SM}	35	35	
Single Pulse Avalanche Current	I_{AS}	15	15	
Single Pulse Avalanche Energy	E_{AS}	11.2	11.2	mJ
Maximum Power Dissipation	P_D	1.98	4.16	W
		1.26	2.66	
		1.38 ^{b, c}	2.35 ^{b, c}	
		0.88 ^{b, c}	1.5 ^{b, c}	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Channel-1		Channel-2		Unit
		Typ	Max	Typ	Max	
Maximum Junction-to-Ambient ^{b, d}	R_{thJA}	72	90	43	53	°C/W
Maximum Junction-to-Foot (Drain)	R_{thJF}	51	63	25	30	

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 Board.
- c. t = 10 sec.
- d. Maximum under Steady State conditions is 125 °C/W (Channel-1) and 100 °C/W (Channel-2).

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ ^a	Max	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	Ch-1	30		V	
		$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	Ch-2	30			
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$	Ch-1	35			
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$	$I_D = 250 \mu\text{A}$	Ch-1	- 6			
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 1 \text{ mA}$	Ch-1	1	2.5		
		$V_{DS} = V_{GS}, I_D = 1 \text{ mA}$	Ch-2	1	2.5		
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$	Ch-1		100		
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$	Ch-2		100	μA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-1		0.001		
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-2		0.05	0.5	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 100^\circ\text{C}$	Ch-1		0.025		
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 100^\circ\text{C}$	Ch-2		3	15	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-1	20			
		$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-2	20		A	
Drain-Source On-State Resistance ^b	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-1		0.014	0.017	
		$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-2		0.0083	0.010	
		$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$	Ch-1		0.016	0.0195	
		$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$	Ch-2		0.0095	0.0115	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 8 \text{ A}$	Ch-1		40		
		$V_{DS} = 15 \text{ V}, I_D = 8 \text{ A}$	Ch-2		47		
Dynamic^a							
Input Capacitance	C_{iss}	Channel-1 $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch-1		1535		
			Ch-2		2290		
Output Capacitance	C_{oss}		Ch-1		205		
			Ch-2		360		
Reverse Transfer Capacitance	C_{rss}	Channel-2 $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch-1		91		
			Ch-2		117		
Total Gate Charge	Q_g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-1		29	44	
		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-2		39	59	
Gate-Source Charge	Q_{gs}	Channel-1 $V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$	Ch-1		12.5	19	
			Ch-2		17	26	
		Channel-2 $V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$	Ch-1		4.1		
			Ch-2		5.6		
Gate-Drain Charge	Q_{gd}	$f = 1 \text{ MHz}$	Ch-1		3.4		
			Ch-2		4		
Gate Resistance	R_g	$f = 1 \text{ MHz}$	Ch-1		1.8	3.0	
			Ch-2		1.9	3.0	

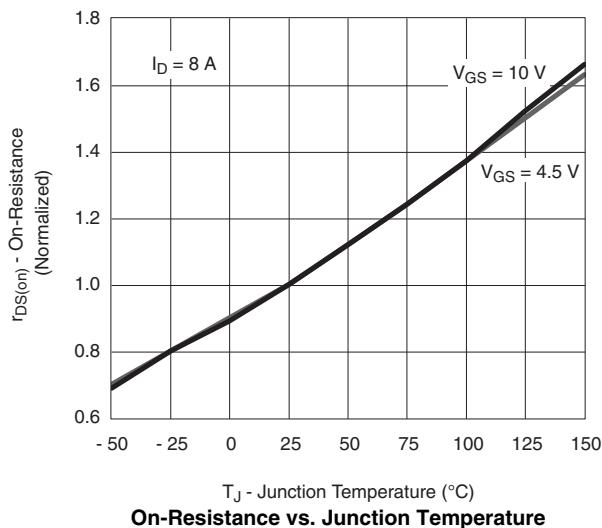
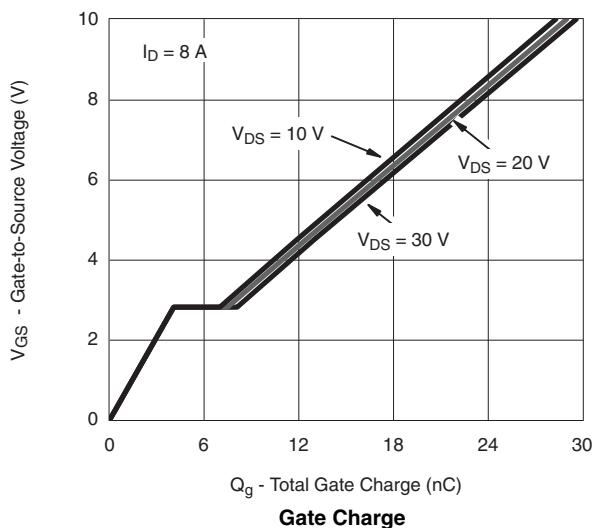
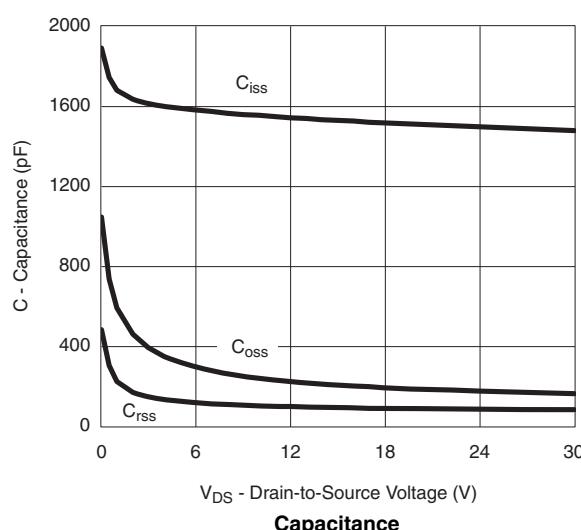
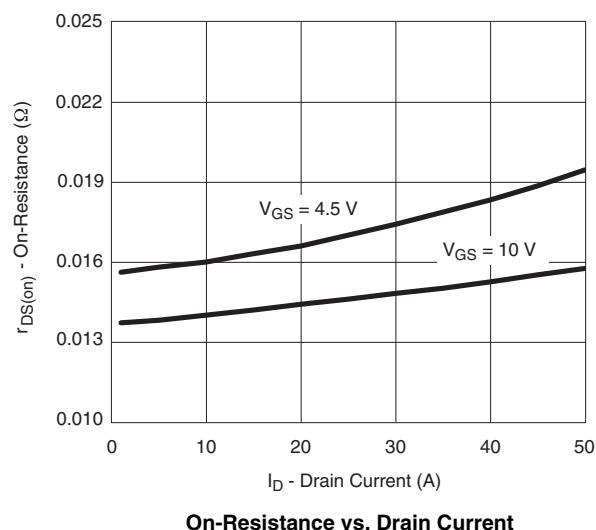
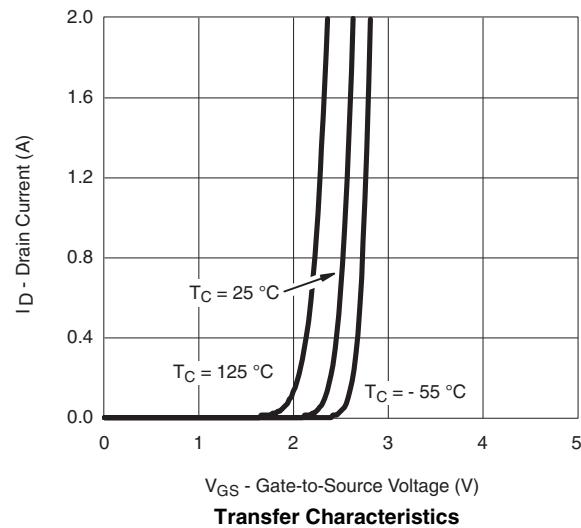
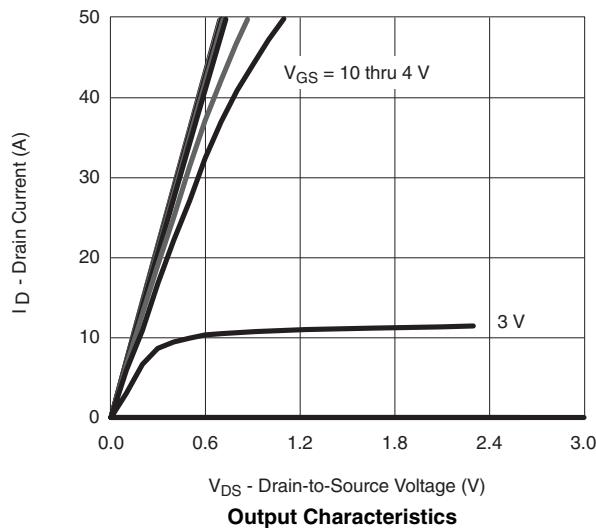
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions			Min	Typ ^a	Max
Dynamic^a							
Turn-On Delay Time	$t_{d(on)}$	Channel-1 $V_{DD} = 15 \text{ V}$, $R_L = 3 \Omega$ $I_D \approx 5 \text{ A}$, $V_{GEN} = 10 \text{ V}$, $R_g = 1 \Omega$	Ch-1		8	15	ns
Rise Time	t_r		Ch-2		9	16	
Turn-Off Delay Time	$t_{d(off)}$		Ch-1		22	33	
Fall Time	t_f		Ch-2		24	36	
Turn-On Delay Time	$t_{d(on)}$		Ch-1		20	30	
Rise Time	t_r		Ch-2		26	39	
Turn-Off Delay Time	$t_{d(off)}$		Ch-1		8	15	
Fall Time	t_f		Ch-2		8	15	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$		Ch-1		1.8	A
Pulse Diode Forward Current ^a	I_{SM}			Ch-2		3.8	
Body Diode Voltage	V_{SD}	$I_S = 2 \text{ A}$	Ch-1		35	V	
Body Diode Reverse Recovery Time	t_{rr}	$I_S = 1 \text{ A}$	Ch-2		35		
Body Diode Reverse Recovery Charge	Q_{rr}	Channel-1 $I_F = 4 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $T_J = 25^\circ\text{C}$	Ch-1		0.77	1.1	ns
Reverse Recovery Fall Time	t_a		Ch-2		0.37	0.43	
Reverse Recovery Rise Time	t_b		Ch-1		22	33	
			Ch-2		26	39	
			Ch-1		15	23	nC
			Ch-2		15	23	
			Ch-1		13		ns
			Ch-2		13		
			Ch-1		9		ns
			Ch-2		13		

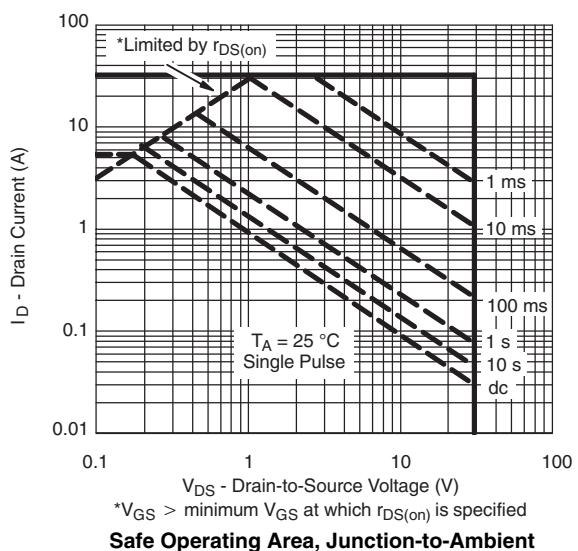
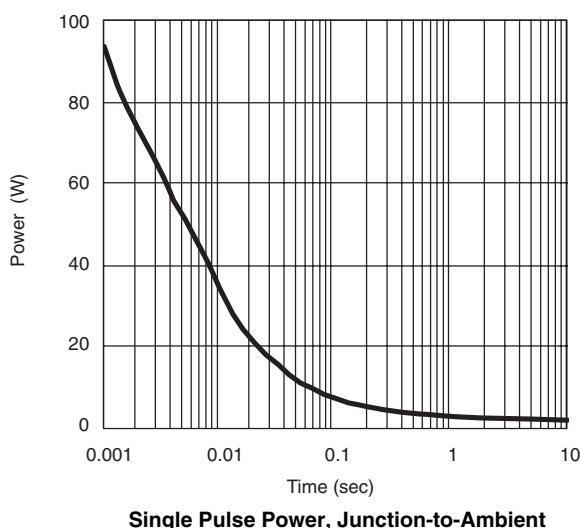
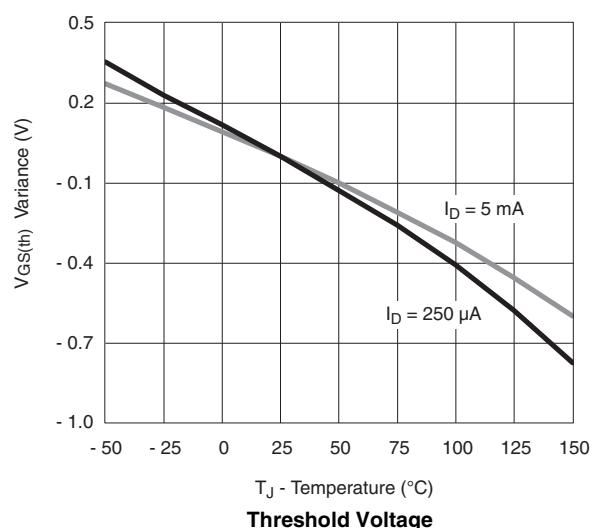
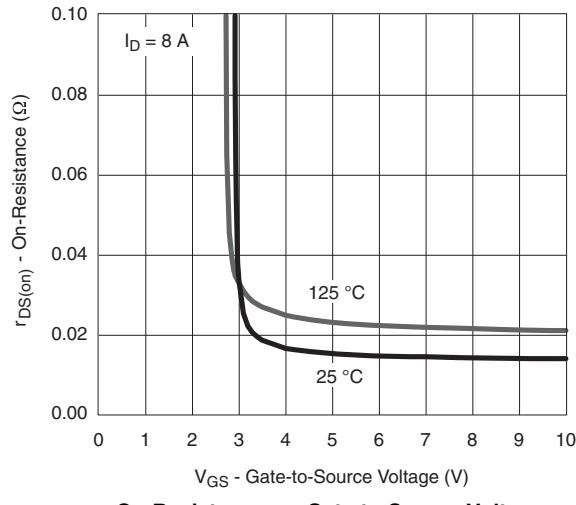
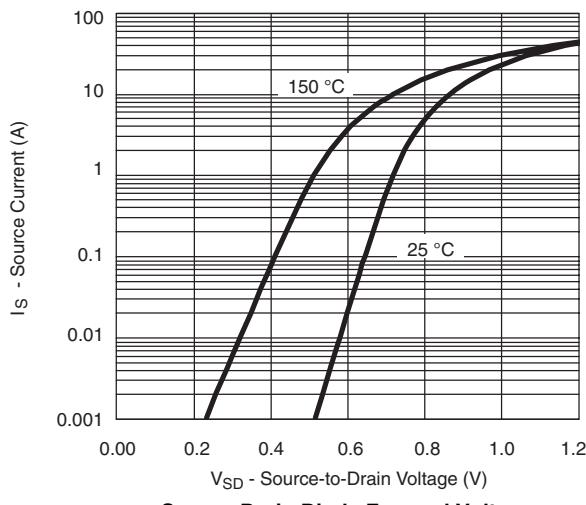
Notes:

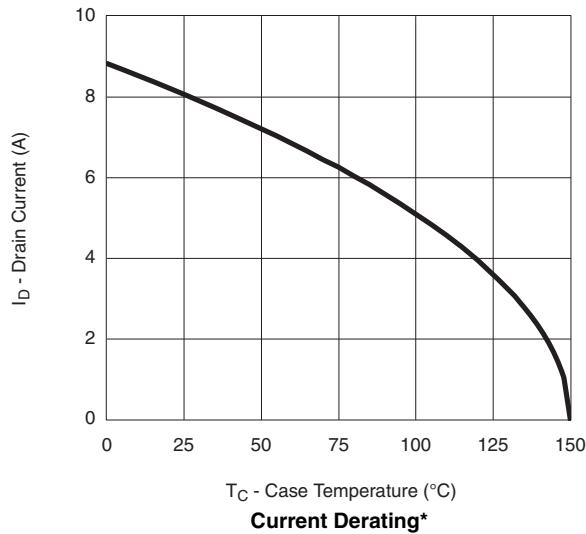
- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

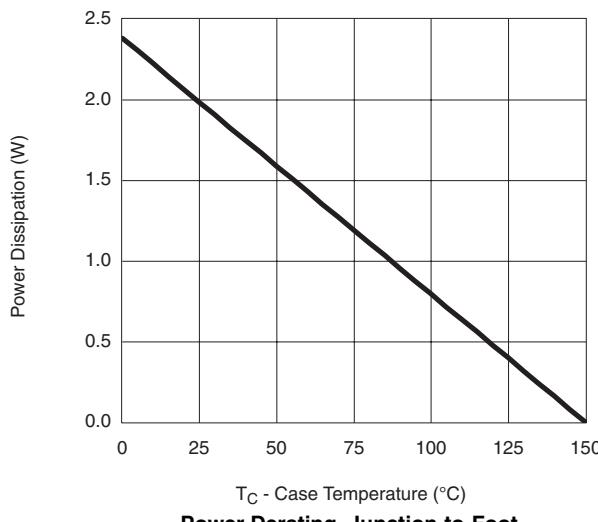
CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



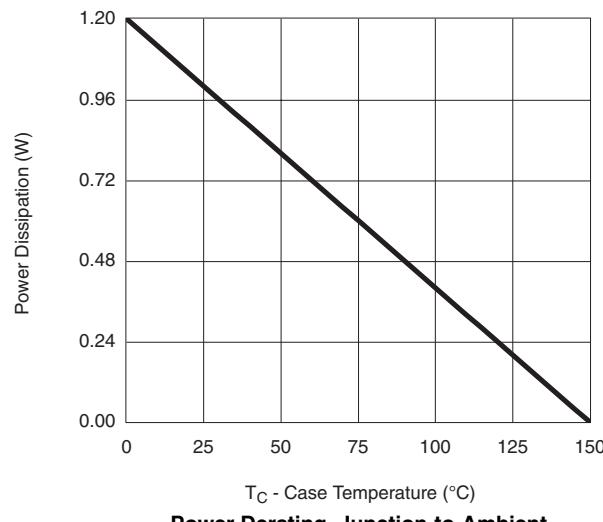
CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted T_C - Case Temperature (°C)

Current Derating*

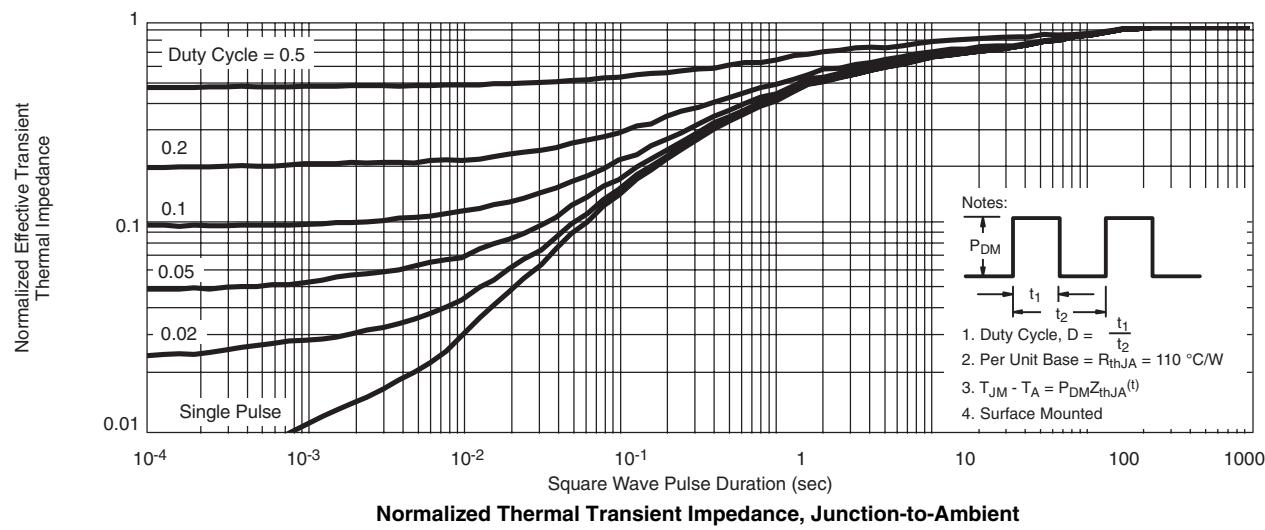
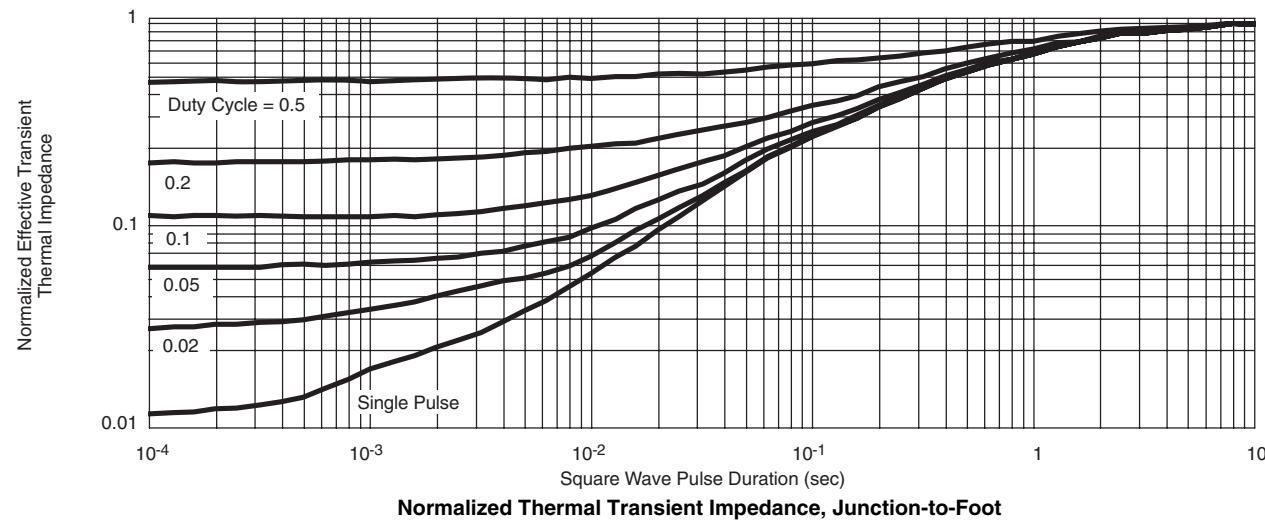
 T_C - Case Temperature (°C)

Power Derating, Junction-to-Foot

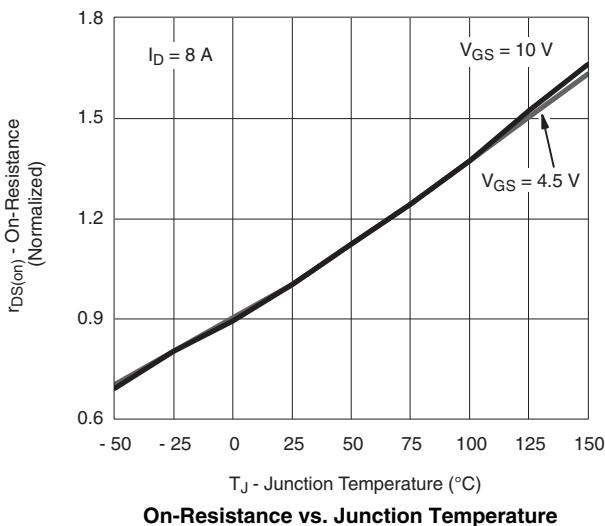
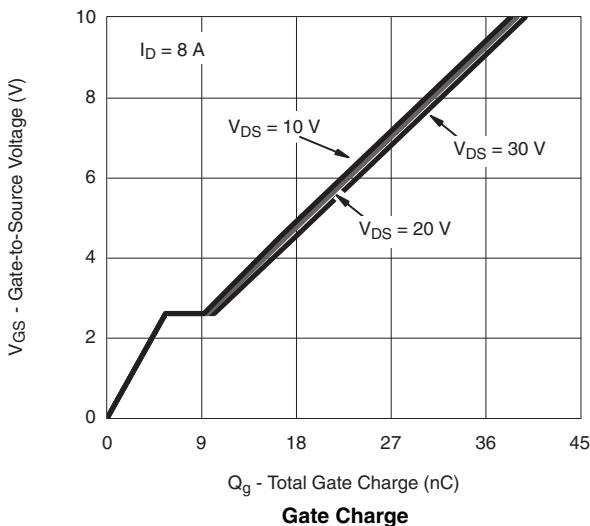
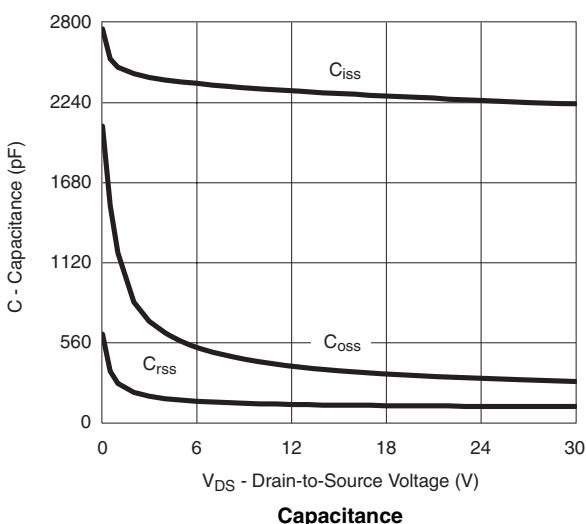
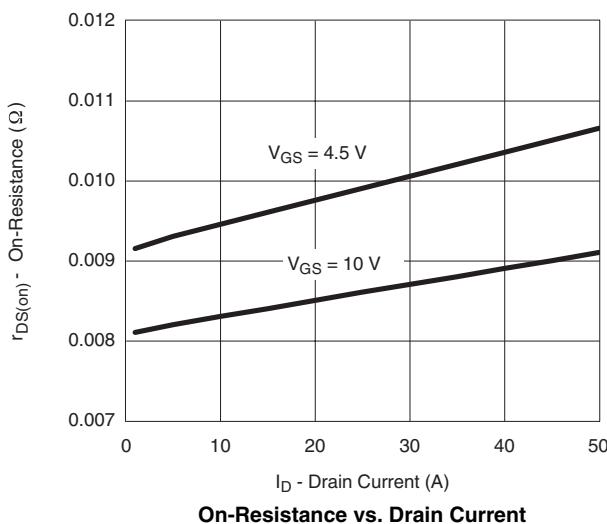
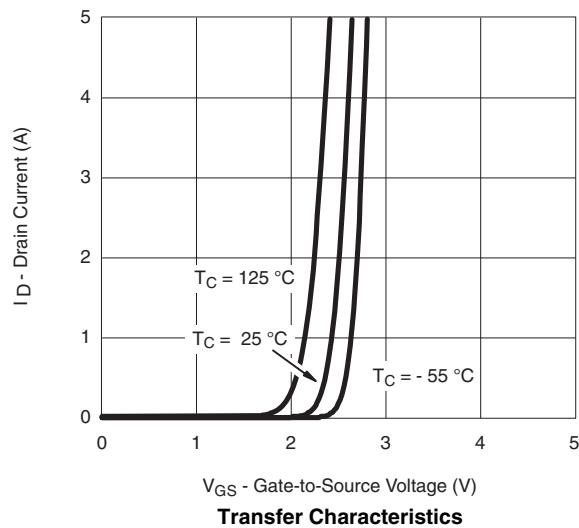
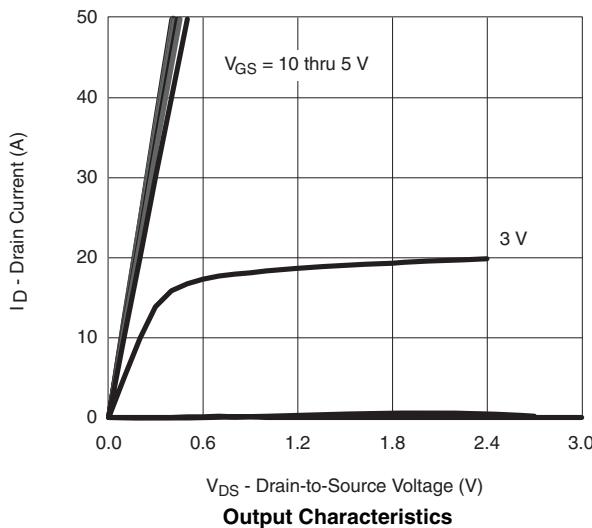
 T_C - Case Temperature (°C)

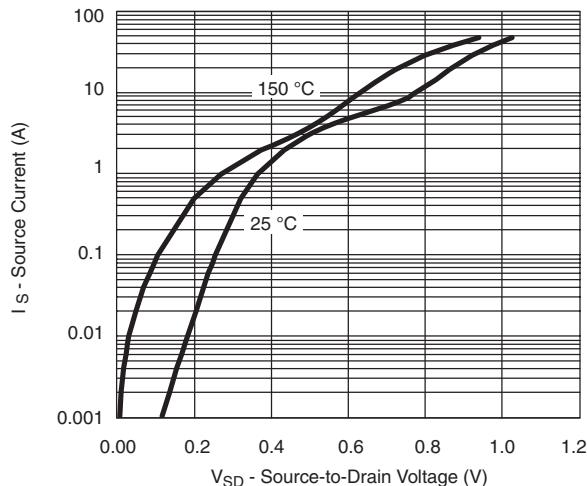
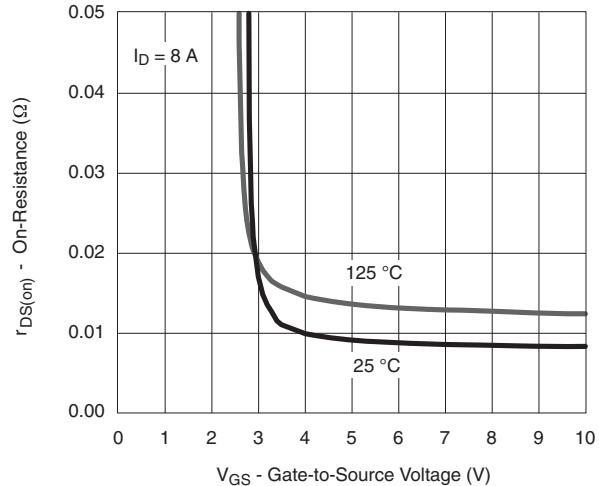
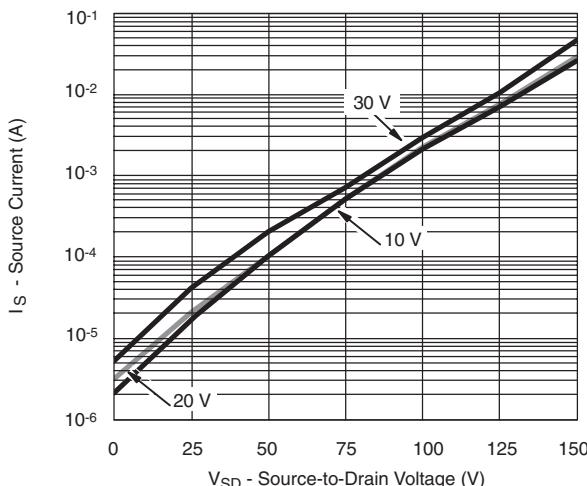
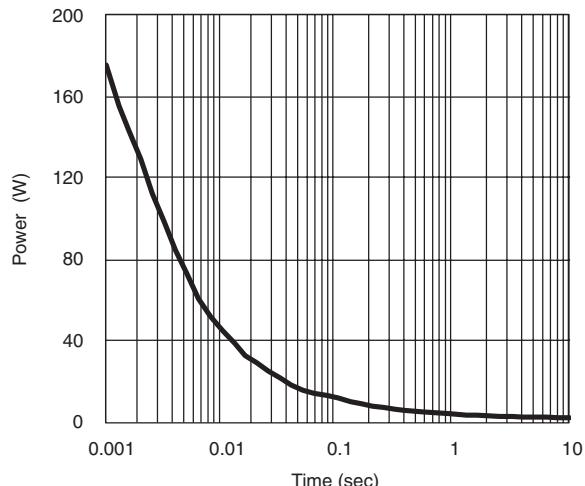
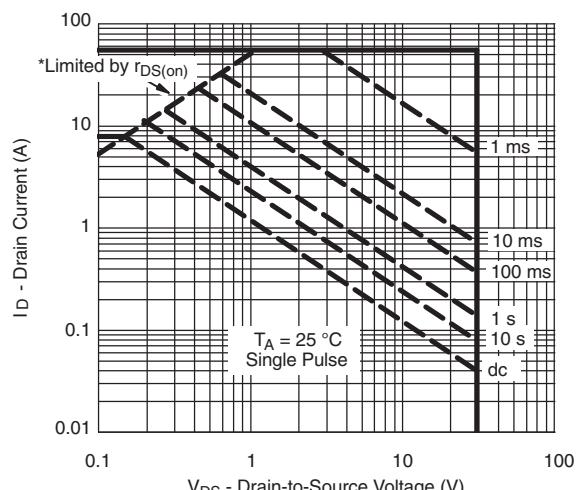
Power Derating, Junction-to-Ambient

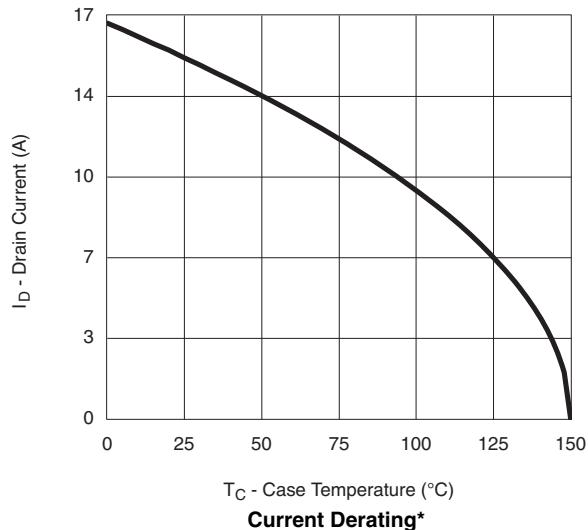
*The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Foot

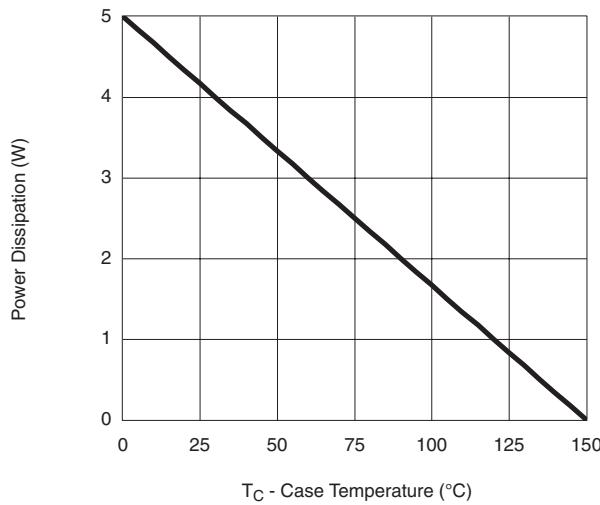
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



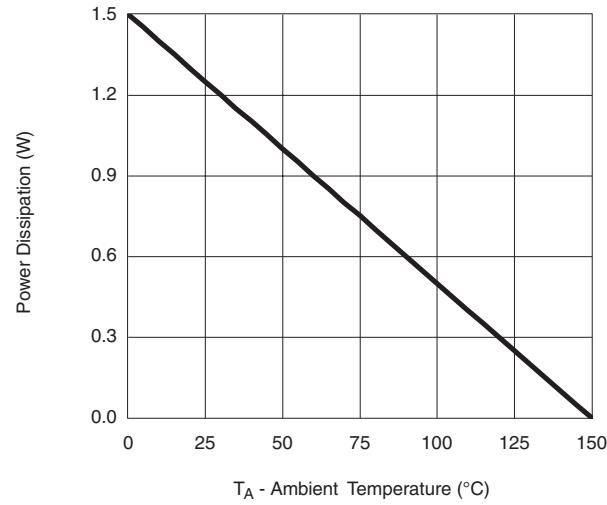
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Reverse Current (Schottky)

Single Pulse Power, Junction-to-Ambient

Safe Operating Area, Junction-to-Ambient

CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted T_C - Case Temperature (°C)

Current Derating*

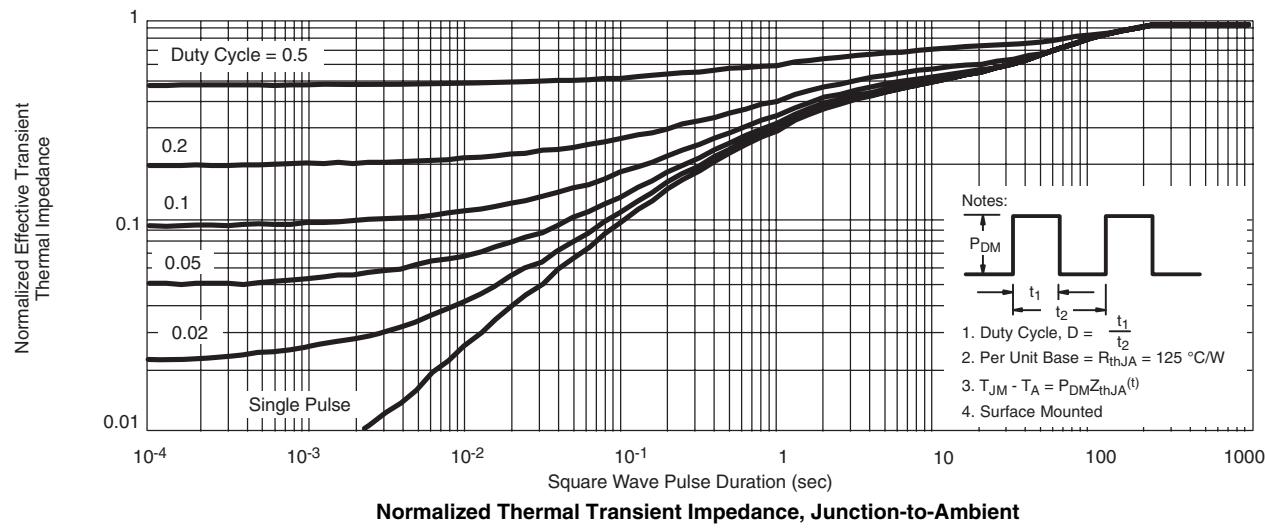
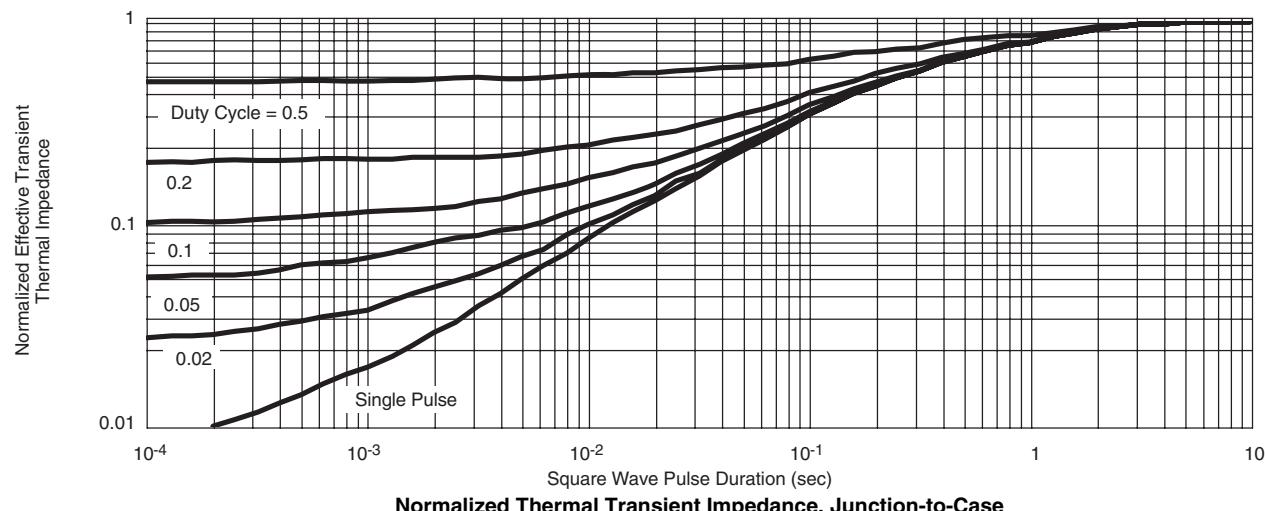
 T_C - Case Temperature (°C)

Power Derating, Junction-to-Foot

 T_A - Ambient Temperature (°C)

Power Derating, Junction-to-Ambient

*The power dissipation P_D is based on $T_{J(\max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Case

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